

claims. The field of search will unquestionably overlap, and a smaller number of method claims will not add to the burden of examination in any substantial fashion.

The basis for the restriction made by the examiner shows that there will be no burden. The examiner states that a different process could be used to make the Group I invention. The exemplary different process suggested by the examiner is one where the extractor and aperture are formed concurrently. Such a process may be used to form the device defined in various ones of the Group I claims, but other claims define a device that will be formed only by a process where the extractor and aperture are formed separately. Because the examiner will search and examine these claims as part of the Group I examination, there is no serious burden associated with also examining the small number of Group II method claims.

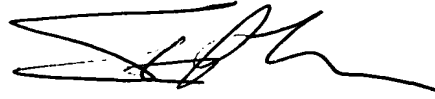
As an example, the examiner's attention is directed to claim 28. Claim 28 defines, in part, an aperture having a $\sim 0.8 - \sim 2\mu\text{m}$ diameter in a device having extractor level focusing means for focusing the emissions from a $\sim 0.3 - \sim 0.5\mu\text{m}$ diameter and $\sim 0.4 - \sim 0.6\mu\text{m}$ deep well. The extractor level focusing means is separated from the aperture, as a focus is required. Accordingly, in the case of claim 28, for example, a separately formed aperture is required. As the examiner will search claim 28 with Group I, there is no serious burden to concurrently examine the small set of method claims that require a step of separately forming an aperture.

Applicants thereby request the examination of Group II along with
elected Group I.

Respectfully submitted,

GREER, BURNS & CRAIN, LTD.

By



Steven P. Fallon

Registration No. 35,132

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300 South Wacker Drive, Suite 2500
Chicago, Illinois 60606
(312) 360-0080
Customer No. 24978